# MOSFET – Power, Single, N-Channel, SO-8 FL 30 V, 52 A

## **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **Applications**

- CPU Power Delivery
- DC-DC Converters

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Volta	age		$V_{GS}$	±20	V
Continuous Drain Current R <sub>0JA</sub> (Note 1)		$T_A = 25^{\circ}C$ $T_A = 80^{\circ}C$	I <sub>D</sub>	16.4 12.3	Α
Power Dissipation R <sub>0JA</sub> (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.51	W
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s}$		$T_A = 25^{\circ}C$ $T_A = 80^{\circ}C$	I <sub>D</sub>	25.3 19.0	Α
(Note 1)  Power Dissipation  R <sub>0,JA</sub> ≤ 10 s (Note 1)	Steady	T <sub>A</sub> = 80 C	P <sub>D</sub>	6.0	W
Continuous Drain Current R <sub>θJA</sub>	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	9.0	Α
(Note 2) Power Dissipation		$T_A = 80^{\circ}C$ $T_A = 25^{\circ}C$	P <sub>D</sub>	6.8 0.76	W
R <sub>θJA</sub> (Note 2)  Continuous Drain  Current R <sub>θJC</sub> (Note 1)		$T_C = 25^{\circ}C$ $T_C = 80^{\circ}C$	I <sub>D</sub>	52 39	Α
Power Dissipation R <sub>0</sub> JC (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	25.5	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	144	Α
Pulsed Source Current (Body Diode)	$T_A = 25^\circ$	$T_A = 25^{\circ}C$ , $t_p = 10 \mu s$		560	Α
Current Limited by Pa	ckage	T <sub>A</sub> = 25°C	I <sub>Dmax</sub>	80	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C	
Source Current (Body Diode)		I <sub>S</sub>	23	Α	
Drain to Source DV/DT		dV/d <sub>t</sub>	7.0	V/ns	
Single Pulse Drain-to-Source Avalanche Energy ( $T_J$ = 25°C, $V_{GS}$ = 10 V, $I_L$ = 29 $A_{pk}$ , $L$ = 0.1 mH, $R_{GS}$ = 25 $\Omega$ ) (Note 3)		E <sub>AS</sub>	42	mJ	
	Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

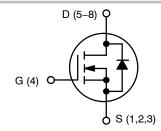
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.



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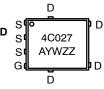
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
20.1/	4.8 mΩ @ 10 V	52 A
30 V	7.47 m $\Omega$ @ 4.5 V	32 A



**N-CHANNEL MOSFET** 







A = Assembly Location Y = Year

W = Work Week
ZZ = Lot Traceability

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4C027NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4C027NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum rating. Parts are 100% tested at  $T_J = 25$ °C,  $V_{GS} = 10$  V,  $I_L = 21$  Apk,  $E_{AS} = 22$  mJ.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.9	
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	49.8	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	164.6	°C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{ heta JA}$	21.0	

- 4. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.5. Surface-mounted on FR4 board using the minimum recommended pad size.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							<b>!</b>
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage (transient)	V <sub>(BR)DSSt</sub>	$V_{GS} = 0 \text{ V}, I_{D(aval)} = 8.4 \text{ A},$ $T_{case} = 25^{\circ}\text{C}, t_{transient} = 100 \text{ ns}$		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				13.8		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1.0	μΑ
			T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.3		2.1	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.9		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 18 A		4.0	4.8	0
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		6.01	7.47	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			42		S
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES					•		•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			1113	1670	
Output Capacitance	C <sub>OSS</sub>				702		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				39		
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15 V, f = 1 MHz			0.035		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			8.4		
Threshold Gate Charge	Q <sub>G(TH)</sub>				1.8		nC
Gate-to-Source Charge	$Q_{GS}$				3.5		
Gate-to-Drain Charge	$Q_{GD}$				3.3		
Gate Plateau Voltage	V <sub>GP</sub>				3.4		V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			18.2		nC

# **SWITCHING CHARACTERISTICS** (Note 7)

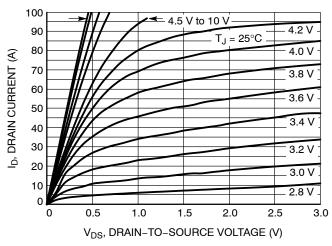
- 6. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
- 7. Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	lote 7)			•	•		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			9.0		ns
Rise Time	t <sub>r</sub>				33		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				15		
Fall Time	t <sub>f</sub>				4.0		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			7.0		ns
Rise Time	t <sub>r</sub>				26		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				19		
Fall Time	t <sub>f</sub>				3.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.79	1.1	
			T <sub>J</sub> = 125°C		0.66		\ \
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 30 A			28.3		ns
Charge Time	ta				14.5		
Discharge Time	t <sub>b</sub>				13.8		
Reverse Recovery Charge	Qpp				15.3		nC

<sup>6.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
7. Switching characteristics are independent of operating junction temperatures.

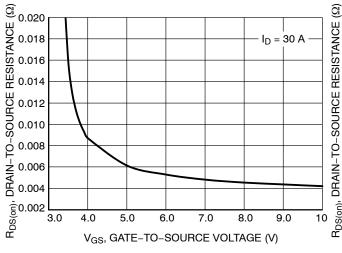
## **TYPICAL CHARACTERISTICS**



80  $V_{DS} = 3 V$ 70 ID, DRAIN CURRENT (A) 60 50 40 30  $T_J = 125^{\circ}C$ 20  $T_J = 25^{\circ}C$ 10  $T_{.1} = -55^{\circ}C$ 0 0.5 2.0 2.5 3.0 3.5 4.0 1.0 1.5 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



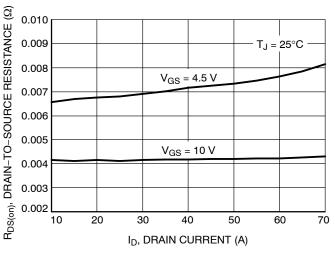
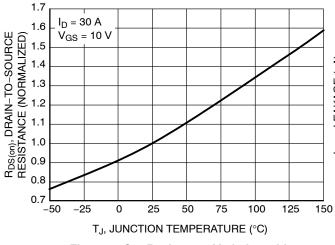


Figure 3. On-Resistance vs. V<sub>GS</sub>

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



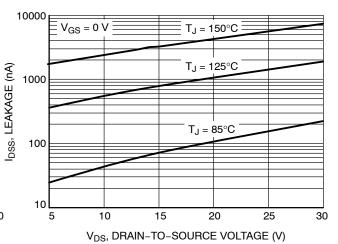


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

## **TYPICAL CHARACTERISTICS**

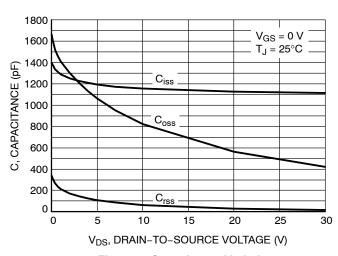


Figure 7. Capacitance Variation

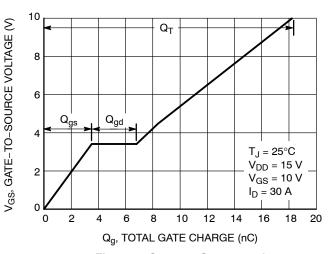


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

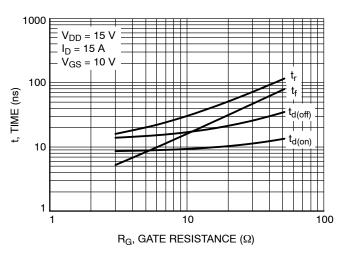


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

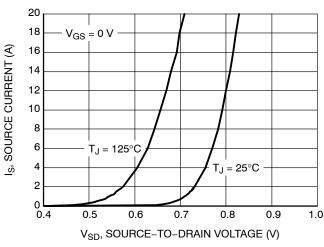


Figure 10. Diode Forward Voltage vs. Current

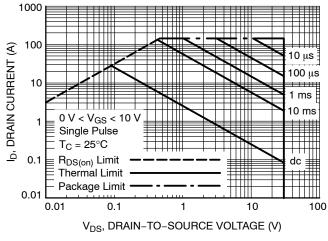


Figure 11. Maximum Rated Forward Biased Safe Operating Area

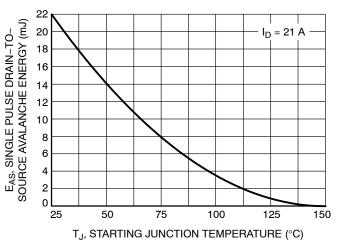


Figure 12. Maximum Avalanche Energy vs.
Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

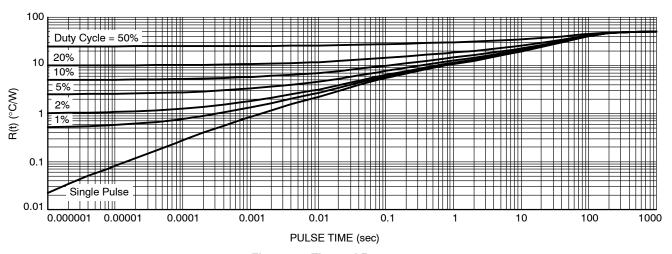


Figure 13. Thermal Response

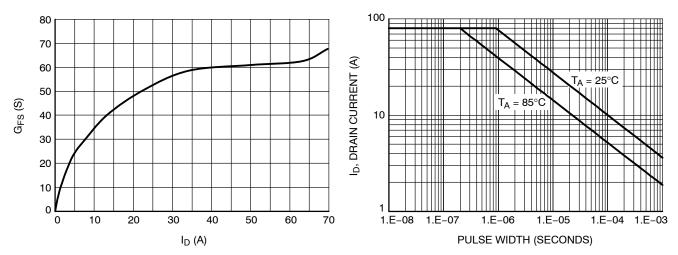
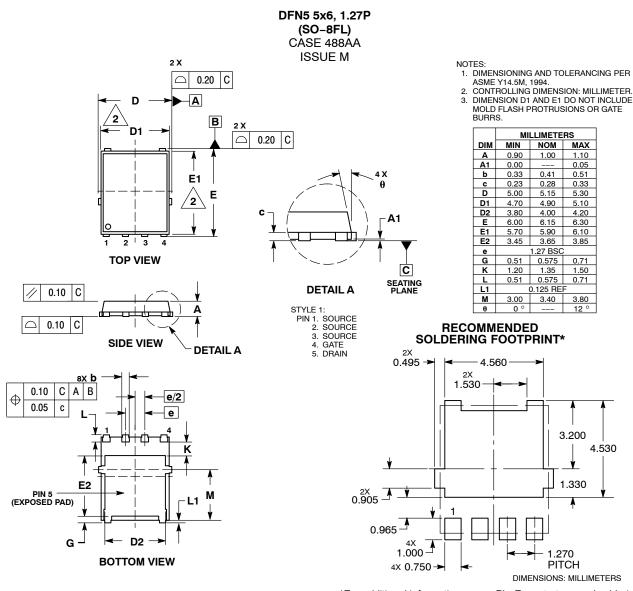


Figure 14. G<sub>FS</sub> vs. I<sub>D</sub> Figure 15. Avalanche Characteristics

## PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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